

Docket No.: 4590-337

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

Emmanuel DE CHAMBOST et al.

Confirmation No.

U.S. Patent Application No. *not yet assigned*Filed: *herewith*

For: DEVICE FOR MEASURING THE EMISSION OF X RAYS PRODUCED BY AN OBJECT
EXPOSED TO AN ELECTRON BEAM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed with the application and no certification or fee is required.

Please note this is a PCT application in the entry of the National Phase in the U.S. and copies of the references cited were transmitted by WIPO and are believed to be in the file of the above-identified application and readily available to the Examiner. Therefore it is believed that Applicants have met all requirements regarding duty of disclosure under 37 CFR 1.56. A copy of the foreign search report is attached for the Examiner's information. Acknowledgement and consideration of these documents are respectfully requested.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)	ATTY. DOCKET NO. 4590-337	U.S. APPLICATION NO. Not yet assigned
	APPLICANT Emmanuel DE CHAMBOST et al.	
	FILING DATE herewith	GROUP

U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	3 760 180 A	09/18/1973	WEBER			
	5 714 757 A	02/03/1998	OSABE et al			

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	01 95365 A	12/13/2001	WO				

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.